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Product News

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Comprehensive Test System Available for Wind Power Applications

The complete **AccuDyne AC Dynamometer system** from SAKOR Technologies, Inc. is now available for wind power testing applications. The system can be used by multiple engineering groups to test and verify designs, as well as for quality control testing after manufacturing. It can be used to test both active and passive wind power driveline components: turbines and their associated blade pitch control motors, generators, and wind-sensing devices and motors, and transmissions. The system can also be used for testing water coolant pumps and other ancillary components. In addition to independent component testing, the AccuDyne can also test groups of components simultaneously to see how they work together. For research and development, the system can be used to simulate the generator itself during early design stages, before a physical generator or gear box unit exists.

Available in sizes ranging from 3 kW to 10 MW, AccuDyne dynamometers are appropriate for all wind power rotational testing needs. Modern vector drive technology allows the AccuDyne system to provide true four-quadrant capability, with seamless crossover between motoring and loading modes. It also offers the most precise speed and torque control available, especially in low-speed applications where full torque can be applied all the way to stall (zero speed).

For more information: SAKOR Technologies Inc., 2855 W. Jolly Road, Okemos, MI 48864; tel: 517/332-7256; fax: 517/332-7250; e-mail: info@sakor.com; web: www.sakor.com.

Atomic Force Microscope Features Closed-Loop 90 µm Scanner

The **7500 atomic force microscope (AFM)**, from Agilent Technologies Inc., is a next-generation platform designed for performance, functionality, and ease-of-use in nanoscale measurement, characterization, and manipulation. The Agilent 7500 achieves atomic resolution imaging with its 90 µm AFM closed-loop scanner. It has an integrated environmental chamber that provides an easily accessible, sealed sample compartment totally isolated from the rest of the system. Humidity and temperature sensors in the chamber track conditions in situ; oxygen and reactive gases can be easily introduced into and purged from the sample chamber.

An optional sample temperature controller for the 7500 allows precise control from −30 to 250 °C (−20 to 480°F), with resolution suitable to experimental requirements. A half-dozen AFM imaging modes are supported by the system's standard nose cone, which can easily be interchanged with specialized nose cones as needed, extending capability. The 7500 comes with the ability to do advanced imaging and electrochemistry applications. Single-pass nanoscale electrical characterization is achievable via Agilent's MAC Mode III controller.

For more information: Agilent Technologies, Inc., P.O. Box 4026, Englewood, CO 80155-4026; tel: 800/829-4444; fax: 800/829-4433; e-mail: usa_orders@agilent.com; web: www.agilent.com/find/7500. ■